捷多邦,专业PCB打样**\$N54种0河54**1世**\$**N74HCT541 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS306A - JANUARY 1996 - REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- High-Current 3-State Outputs Interface Directly With System Bus or Can Drive up to 15 LSTTL Loads
- Data Flow-Through Pinout (All Inputs on Opposite Side From Outputs)
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
 300-mil DIPs

description

These octal buffers and line drivers are designed to have the performance of the popular 'HC240 series and to offer a pinout with inputs and outputs on opposite sides of the package. This arrangement greatly facilitates printed circuit board layout.

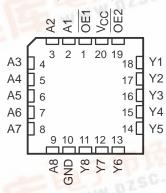
The 3-state control gate is a 2-input NOR. If either output-enable (OE1 or OE2) input is high, all eight outputs are in the high-impedance state. The 'HCT541 provide true data at the outputs.

The SN54HCT541 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT541 is characterized for operation from –40°C to 85°C.

PRODUCTION DATA information is current as of publication date. roducts conform to specifications per the terms of Texas Instruments randard warranty. Production processing does not necessarily include esting of all parameters. SN54HCT541 ... J OR W PACKAGE SN74HCT541 ... DW OR N PACKAGE (TOP VIEW)



SN54HCT541 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer/driver)

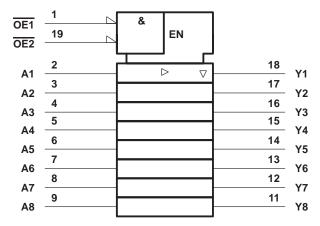
- 0	INPUT	OUTPUT	
OE	1 OE2	Α	Υ
L	L	L	L
L	L	Н	Н
Н	Χ	Χ	Z
X	Н	Х	Z

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SN54HCT541, SN74HCT541 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

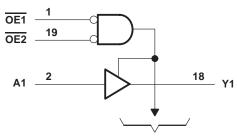
SCLS306A - JANUARY 1996 - REVISED MAY 1997

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC}) (see Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ _{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{stq}	−65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

SN54HCT541, SN74HCT541 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS SCLS306A – JANUARY 1996 – REVISED MAY 1997

recommended operating conditions

	_			54HCT5	41	SN74HCT541			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	V _{CC} = 4.5 V to 5.5 V	2			2			V
V _{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0		0.8	0		0.8	V
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
t _t	Input transition (rise and fall) time		0		500	0		500	ns
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	T _A = 25°C			SN54HCT541		SN74HCT541		UNIT
PARAMETER			VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Vou	VI = VIH or VIL	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
Voн	AI = AIH OL AIL	$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
Voi	\/ı = \/u + or \/u	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL	$\Lambda I = \Lambda IH$ or $\Lambda I\Gamma$	I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33]
lj	$V_I = V_{CC}$ or 0		5.5 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	5.5 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	IO = 0	5.5 V			8		160		80	μΑ
Δl _{CC} †	One input at 0.5 V of Other inputs at 0 or		5.5 V		1.4	2.4		3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то		T,	չ = 25°C	;	SN54H	CT541	SN74H	CT541	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
.	А	Y	4.5 V		13	23		34		29		
^t pd	A	,	5.5 V		12	21		31		26	ns	
	ŌĒ	Y	4.5 V		21	30		45		38	ne	
t _{en}	OE	T	•	5.5 V		19	27		41		34	ns
+	ŌĒ	OE Y	4.5 V		19	30		45		38	ns	
^t dis			ı	'	5.5 V		18	27		41		34
		V	4.5 V		8	12		18		15	no	
t _t		*	5.5 V		7	11		16		14	ns	



SN54HCT541, SN74HCT541 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS SCLS306A – JANUARY 1996 – REVISED MAY 1997

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

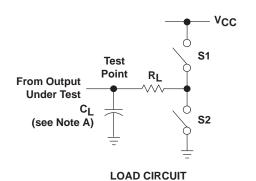
PARAMETER	FROM	FROM TO		T,	ղ = 25°C	;	SN54H	CT541	SN74H	CT541	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
	^	Y	4.5 V		20	33		49		42	20		
^t pd	A		5.5 V		19	30		45		38	ns		
	ŌĒ	V	4.5 V		26	40		60		50	20		
^t en		OE OE	T T	ı	'	5.5 V		25	36		54		45
t _t		Y	4.5 V		17	42		63		53	no		
			5.5 V		14	38		57		48	ns		

operating characteristics, $T_A = 25^{\circ}C$

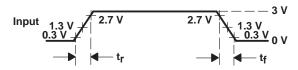
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

SCLS306A - JANUARY 1996 - REVISED MAY 1997

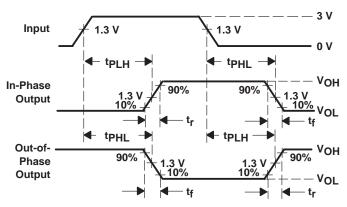
PARAMETER MEASUREMENT INFORMATION

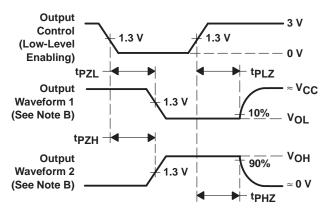


PARA	METER	RL	CL	S1	S2	
	tpZH 1 kΩ 50 pF tpZL 1 kΩ or 150 pF			Open	Closed	
^t en			150 pF	Closed	Open	
4	tPHZ	1 kΩ	50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pr	Closed	Open	
t _{pd} or t _t		_	50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORM INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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